

Notice of References Cited

Application/Control No.

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Applicant(s)/Patent Under
Reexamination
TAKUMAI ET AL.

Examiner

DEVONA E. FAULK

Art Unit

2614

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
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*	N	JP 06225379 A	08-1994	Japan	FURUTA et al.	H04R 1/40
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NON-PATENT DOCUMENTS

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